

CD4073BMS, CD4081BMS, CD4082BMS

CMOS AND Gate

FN3324 Rev 1.00 October 2015

Features

- · High-Voltage Types (20V Rating)
- CD4073BMS Triple 3-Input AND Gate (No longer available or supported)
- · CD4081BMS Quad 2-Input AND Gate
- CD4082BMS Dual 4-Input AND Gate (No longer available or supported)
- Medium Speed Operation:
 - tPLH, tPHL = 60ns (typ) at VDD = 10V
- 100% Tested for Quiescent Current at 20V
- Maximum Input Current of 1μA at 18V Over Full Package Temperature Range; 100nA at 18V and +25°C
- Noise Margin (Over Full Package Temperature Range):
 - 1V at VDD = 5V
 - 2V at VDD = 10V
 - 2.5V at VDD = 15V
- Standardized Symmetrical Output Characteristics
- 5V, 10V and 15V Parametric Ratings
- Meets All Requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

Description

CD4073BMS, CD4081BMS and CD4082BMS AND gates provide the system designer with direct implementation of the AND function and supplement the existing family of CMOS gates.

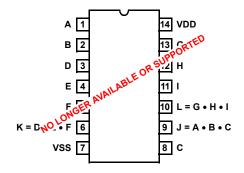
The CD4073BMS, CD4081BMS and CD4082BMS are supplied in these 14 lead outline packages:

Braze Seal DIP *H4Q †H4H

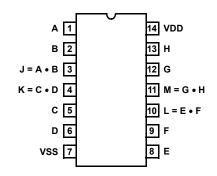
Frit Seal DIP *H1B Ceramic Flatpack *H3W

Pinout

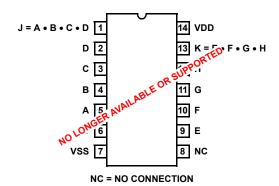
CD4073BMS TOP VIEW



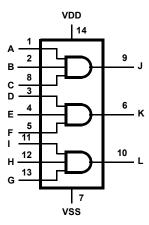
CD4081BMS TOP VIEW



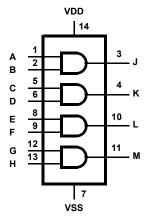
CD4082BMS TOP VIEW



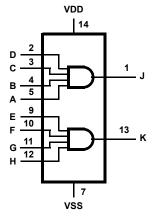
Functional Diagram



CD4073BMS



CD4081BMS



CD4082BMS

intersil*

Absolute Maximum Ratings

DC Supply Voltage Range, (VDD)....-0.5V to +20V (Voltage Referenced to VSS Terminals) Input Voltage Range, All Inputs -0.5V to VDD +0.5V Operating Temperature Range -55°C to +125°C Package Types D, F, K, H Storage Temperature Range (TSTG) -65°C to +150°C Lead Temperature (During Soldering) +265°C At Distance $1/16 \pm 1/32$ Inch (1.59mm \pm 0.79mm) from case for 10s Maximum

Reliability Information

Thermal Resistance	θ_{ja}	$\theta_{\sf jc}$
Ceramic DIP and FRIT Package	80°C/W	20°C/W
Flatpack Package	70°C/W	20°C/W
Maximum Package Power Dissipation (PD	o) at +125°C	;
For TA = -55°C to +100°C (Package Ty	pe D, F, K)	500mW
For TA = $+100^{\circ}$ C to $+125^{\circ}$ C (Package 7	Гуре D, F, K	() Derate
Lin	earity at 12r	mW/°C to 200mW
Device Dissipation per Output Transistor.		100mW
For TA = Full Package Temperature Ra	nge (All Pad	kage Types)
Junction Temperature		+175°C

TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS

				GROUP A		LIM	IITS	
PARAMETER	SYMBOL	CONDITIONS (NOTE 1)	SUBGROUPS	TEMPERATURE	MIN	MAX	UNITS
Supply Current	IDD	VDD = 20V, VIN = VDI	(DD = 20V, VIN = VDD or GND		+25°C	-	.5	μА
					+125°C	-	50	μΑ
		VDD = 18V, VIN = VDI	O or GND	3	-55°C	-	.5	μΑ
Input Leakage Current	IIL	VIN = VDD or GND	VDD = 20	1	+25°C	-100	-	nA
				2	+125°C	-1000	-	nA
			VDD = 18V	3	-55°C	-100	-	nA
Input Leakage Current	IIH	VIN = VDD or GND	VDD = 20	1	+25°C	-	100	nA
				2	+125°C	-	1000	nA
			VDD = 18V	3	-55°C	-	100	nA
Output Voltage	VOL15	VDD = 15V, No Load		1, 2, 3	+25°C, +125°C, -55°C	-	50	mV
Output Voltage	VOH15	VDD = 15V, No Load (Note 3)	1, 2, 3	+25°C, +125°C, -55°C	14.95	-	V
Output Current (Sink)	IOL5	VDD = 5V, VOUT = 0.4	1V	1	+25°C	0.53	-	mA
Output Current (Sink)	IOL10	VDD = 10V, VOUT = 0	.5V	1	+25°C	1.4	-	mA
Output Current (Sink)	IOL15	VDD = 15V, VOUT = 1	.5V	1	+25°C	3.5	-	mA
Output Current (Source)	IOH5A	VDD = 5V, VOUT = 4.6	6V	1	+25°C	-	-0.53	mA
Output Current (Source)	IOH5B	VDD = 5V, VOUT = 2.5	5V	1	+25°C	-	-1.8	mA
Output Current (Source)	IOH10	VDD = 10V, VOUT = 9	.5V	1	+25°C	-	-1.4	mA
Output Current (Source)	IOH15	VDD = 15V, VOUT = 1	3.5V	1	+25°C	-	-3.5	mA
N Threshold Voltage	VNTH	VDD = 10V, ISS = -10µ	ιA	1	+25°C	-2.8	-0.7	V
P Threshold Voltage	VPTH	VSS = 0V, IDD = 10μA	ı	1	+25°C	0.7	2.8	V
Functional	F	VDD = 2.8V, VIN = VD	D or GND	7	+25°C	VOH >	VOL <	V
		VDD = 20V, VIN = VDI	O or GND	7	+25°C	VDD/2	VDD/2	
		VDD = 18V, VIN = VDI	O or GND	8A	+125°C			
		VDD = 3V, VIN = VDD	or GND	8B	-55°C			
Input Voltage Low (Note 2)	VIL	VDD = 5V, VOH > 4.5\	/, VOL < 0.5V	1, 2, 3	+25°C, +125°C, -55°C	=	1.5	V
Input Voltage High (Note 2)	VIH	VDD = 5V, VOH > 4.5\	/, VOL < 0.5V	1, 2, 3	+25°C, +125°C, -55°C	3.5	-	V
Input Voltage Low (Note 2)	VIL	VDD = 15V, VOH > 13 VOL < 1.5V	.5V,	1, 2, 3	+25°C, +125°C, -55°C	-	4	V
Input Voltage High (Note 2)	VIH	VDD = 15V, VOH > 13 VOL < 1.5V	.5V,	1, 2, 3	+25°C, +125°C, -55°C	11	-	V

2. Go/No Go test with limits applied to inputs.



NOTES: 1. All voltages referenced to device GND, 100% testing being im- 3. For accuracy, voltage is measured differentially to VDD. Limit is 0.050V max.

TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS

			GROUP A		LIM	IITS	
PARAMETER	SYMBOL	CONDITIONS (NOTES 1, 2)	SUBGROUPS	TEMPERATURE	MIN	MAX	UNITS
Propagation Delay TPHL TPLH		VDD = 5V, VIN = VDD or GND	9	+25°C	-	250	ns
			10, 11	+125°C, -55°C	-	338	ns
Transition Time	TTHL	VDD = 5V, VIN = VDD or GND	9	+25°C	-	200	ns
	TTLH		10, 11	+125°C, -55°C	-	270	ns

NOTES:

- 1. CL = 50pF, RL = 200K, Input TR, TF < 20ns.
- 2. -55°C and +125°C limits guaranteed, 100% testing being implemented.

TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS

					LIMITS			
PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	MIN	MAX	UNITS	
Supply Current	IDD	VDD = 5V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	.25	μΑ	
				+125°C	-	7.5	μА	
		VDD = 10V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	.5	μА	
				+125°C	-	15	μΑ	
		VDD = 15V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	.5	μΑ	
				+125°C	-	30	μΑ	
Output Voltage	VOL	VDD = 5V, No Load	1, 2	+25°C, +125°C, - 55°C	-	50	mV	
Output Voltage	VOL	VDD = 10V, No Load	1, 2	+25°C, +125°C, - 55°C	-	50	mV	
Output Voltage	VOH	VDD = 5V, No Load	1, 2	+25°C, +125°C, - 55°C	4.95	-	V	
Output Voltage	VOH	VDD = 10V, No Load	1, 2	+25°C, +125°C, - 55°C	9.95	-	V	
Output Current (Sink)	IOL5	VDD = 5V, VOUT = 0.4V	1, 2	+125°C	0.36	-	mA	
				-55°C	0.64	-	mA	
Output Current (Sink)	IOL10	VDD = 10V, VOUT = 0.5V	1, 2	+125°C	0.9	-	mA	
				-55°C	1.6	-	mA	
Output Current (Sink)	IOL15	VDD = 15V, VOUT = 1.5V	1, 2	+125°C	2.4	-	mA	
				-55°C	4.2	-	mA	
Output Current (Source)	IOH5A	VDD = 5V, VOUT = 4.6V	1, 2	+125°C	-	-0.36	mA	
				-55°C	-	-0.64	mA	
Output Current (Source)	IOH5B	VDD = 5V, VOUT = 2.5V	1, 2	+125°C	-	-1.15	mA	
				-55°C	-	-2.0	mA	
Output Current (Source)	IOH10	VDD = 10V, VOUT = 9.5V	1, 2	+125°C	-	-0.9	mA	
				-55°C	-	-2.6	mA	
Output Current (Source)	IOH15	VDD =15V, VOUT = 13.5V	1, 2	+125°C	-	-2.4	mA	
				-55°C	-	-4.2	mA	
Input Voltage Low	VIL	VDD = 10V, VOH > 9V, VOL < 1V	1, 2	+25°C, +125°C, - 55°C	-	3	V	
Input Voltage High	VIH	VDD = 10V, VOH > 9V, VOL < 1V	1, 2	+25°C, +125°C, - 55°C	7	-	V	
Propagation Delay	TPHL	VDD = 10V	1, 2, 3	+25°C	-	120	ns	
	TPLH	VDD = 15V	1, 2, 3	+25°C	-	90	ns	



TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)

					LIMITS		
PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	MIN	MAX	UNITS
Transition Time		VDD = 10V	1, 2, 3	+25°C	-	100	ns
	TTLH	VDD = 15V	1, 2, 3	+25°C	-	80	ns
Input Capacitance	CIN	Any Input	1, 2	+25°C	-	7.5	pF

NOTES:

- 1. All voltages referenced to device GND.
- 2. The parameters listed on Table 3 are controlled via design or process and are not directly tested. These parameters are characterized on initial design release and upon design changes which would affect these characteristics.
- 3. CL = 50pF, RL = 200K, Input TR, TF < 20ns.

TABLE 4. POST IRRADIATION ELECTRICAL PERFORMANCE CHARACTERISTICS

					LIM	IITS	
PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	MIN	MAX	UNITS
Supply Current	IDD	VDD = 20V, VIN = VDD or GND	1, 4	+25°C	-	2.5	μΑ
N Threshold Voltage	VNTH	VDD = 10V, ISS = -10μA	1, 4	+25°C	-2.8	-0.2	V
N Threshold Voltage Delta	ΔVTN	VDD = 10V, ISS = -10μA	1, 4	+25°C	-	±1	V
P Threshold Voltage	VTP	VSS = 0V, IDD = 10μA	1, 4	+25°C	0.2	2.8	V
P Threshold Voltage Delta	ΔVΤΡ	$VSS = 0V, IDD = 10\mu A$	1, 4	+25°C	-	±1	V
Functional	F	VDD = 18V, VIN = VDD or GND	1	+25°C	VOH >	VOL <	V
		VDD = 3V, VIN = VDD or GND			VDD/2	VDD/2	
Propagation Delay Time	TPHL TPLH	VDD = 5V	1, 2, 3, 4	+25°C	-	1.35 x +25°C Limit	ns

NOTES: 1. All voltages referenced to device GND.

3. See Table 2 for +25°C limit.

2. CL = 50pF, RL = 200K, Input TR, TF < 20ns.

4. Read and Record

TABLE 5. BURN-IN AND LIFE TEST DELTA PARAMETERS +25°C

PARAMETER	SYMBOL	DELTA LIMIT
Supply Current - SSI	IDD	±0.1μΑ
Output Current (Sink)	IOL5	± 20% x Pre-Test Reading
Output Current (Source)	IOH5A	\pm 20% x Pre-Test Reading

TABLE 6. APPLICABLE SUBGROUPS

CONFORMANCE GROUP	MIL-STD-883 METHOD	GROUP A SUBGROUPS	READ AND RECORD
Initial Test (Pre Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A
Interim Test 1 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A
Interim Test 2 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A
PDA (Note 1)	100% 5004	1, 7, 9, Deltas	
Interim Test 3 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A
PDA (Note 1)	100% 5004	1, 7, 9, Deltas	
Final Test	100% 5004	2, 3, 8A, 8B, 10, 11	
Group A	Sample 5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	



TABLE 6. APPLICABLE SUBGROUPS (Continued)

CONFORMANCE GROUP		MIL-STD-883 METHOD	GROUP A SUBGROUPS	READ AND RECORD
Group B	Subgroup B-5	Sample 5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11, Deltas	Subgroups 1, 2, 3, 9, 10, 11
	Subgroup B-6	Sample 5005	1, 7, 9	
Group D		Sample 5005	1, 2, 3, 8A, 8B, 9	Subgroups 1, 2 3

NOTE: 1.5% Parameteric, 3% Functional; Cumulative for Static 1 and 2.

TABLE 7. TOTAL DOSE IRRADIATION

	MIL-STD-883	MIL-STD-883 TEST		READ AND RECORD	
CONFORMANCE GROUPS	METHOD	PRE-IRRAD	POST-IRRAD	PRE-IRRAD	POST-IRRAD
Group E Subgroup 2	5005	1, 7, 9	Table 4	1, 9	Table 4

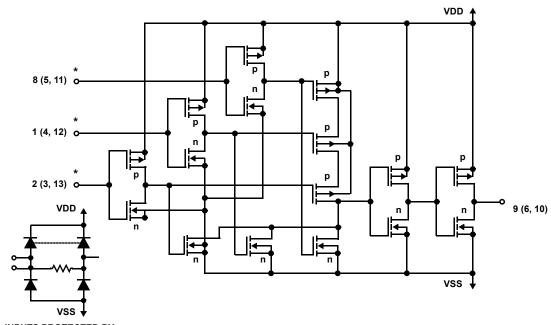
TABLE 8. BURN-IN AND IRRADIATION TEST CONNECTIONS

					OSCILLA	ATOR
FUNCTION	OPEN	GROUND	VDD	$\text{9V} \pm \text{-0.5V}$	50kHz	25kHz
PART NUMBER	CD4073BMS					
Static Burn-In 1 Note 1	6, 9, 10	1 - 5, 7, 8, 11 - 13	14			
Static Burn-In 2 Note 1	6, 9, 10	7	1 - 5, 8, 11 - 14			
Dynamic Burn- In Note 1	-	7	14	6, 9, 10	1, 5, 8, 11 - 13	
Irradiation Note 2	6, 9, 10	7	1 - 5, 8, 11 - 14			
PART NUMBER	CD4081BMS					
Static Burn-In 1 Note 1	3, 4, 10, 11	1, 2, 5 - 9, 12, 13	14			
Static Burn-In 2 Note 1	3, 4, 10, 11	7	1, 2, 5, 6, 8, 9, 12 - 14			
Dynamic Burn- In Note 1	-	7	14	3, 4, 10, 11	1, 2, 5, 6, 8, 9, 12, 13	
Irradiation Note 2	3, 4, 10, 11	7	1, 2, 5, 6, 8, 9, 12 - 14			
PART NUMBER	CD4082BMS					
Static Burn-In 1 Note 1	1, 6, 8, 13	2 - 5, 7, 9 - 12	14			
Static Burn-In 2 Note 1	1, 6, 8, 13	7	2 - 5, 9 - 12, 14			
Dynamic Burn- In Note 1	6, 8	7	14	1, 3	2 - 5, 9 - 12	
Irradiation Note 2	1, 6, 8, 13	7	2 - 5, 9 - 12, 14			

NOTE:

- 1. Each pin except VDD and GND will have a series resistor of 10K \pm 5%, VDD = 18V \pm 0.5V
- 2. Each pin except VDD and GND will have a series resistor of $47K \pm 5\%$; Group E, Subgroup 2, sample size is 4 dice/wafer, 0 failures, VDD = $10V \pm 0.5V$





ALL INPUTS PROTECTED BY CMOS PROTECTION NETWORK

FIGURE 1. SCHEMATIC DIAGRAM FOR CD4073BMS (1 OF 3 IDENTICAL GATES)

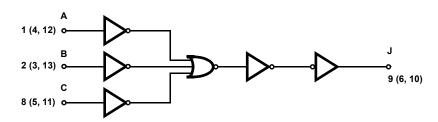


FIGURE 2. LOGIC DIAGRAM FOR CD4073BMS (1 OF 3 IDENTICAL GATES)

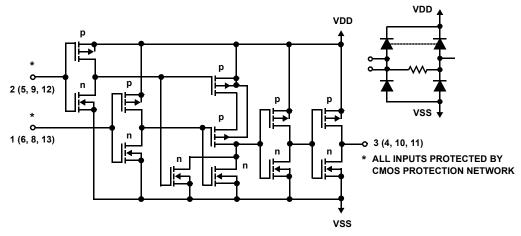


FIGURE 3. SCHEMATIC DIAGRAM FOR CD4081BMS (1 OF 4 IDENTICAL GATES)

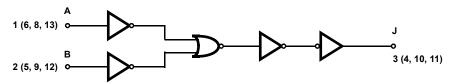


FIGURE 4. LOGIC DIAGRAM FOR CD4081BMS (1 OF 4 IDENTICAL GATES)

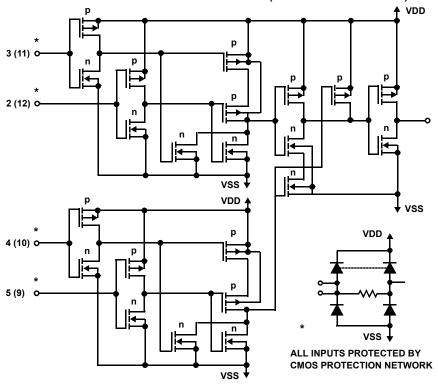


FIGURE 5. SCHEMATIC DIAGRAM FOR CD4082BMS (1 OF 2 IDENTICAL GATES)

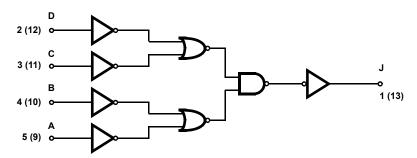


FIGURE 6. LOGIC DIAGRAM FOR CD4082BMS (1 OF 2 IDENTICAL GATES)

Typical Performance Characteristics

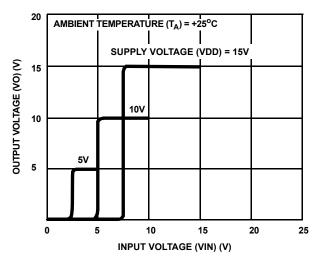


FIGURE 7. TYPICAL VOLTAGE TRANSFER CHARACTERISTICS

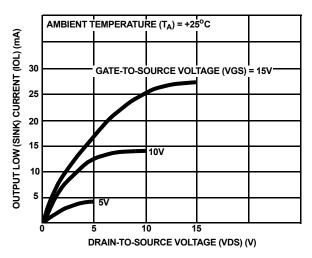


FIGURE 9. TYPICAL OUTPUT LOW (SINK) CURRENT CHARACTERISTICS

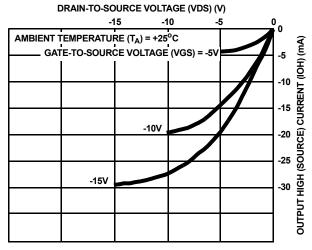


FIGURE 11. TYPICAL OUTPUT HIGH (SOURCE) CURRENT CHARACTERISTICS

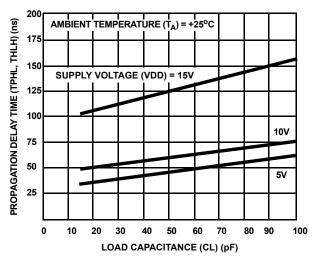


FIGURE 8. TYPICAL PROPAGATION DELAY TIME AS A FUNCTION OF LOAD CAPACITANCE

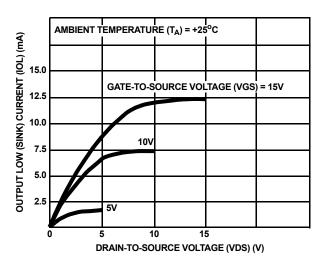


FIGURE 10. MINIMUM OUTPUT LOW (SINK) CURRENT CHARACTERISTICS

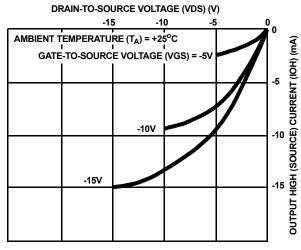


FIGURE 12. MINIMUM OUTPUT HIGH (SOURCE) CURRENT CHARACTERISTICS



Typical Performance Characteristics (Continued)

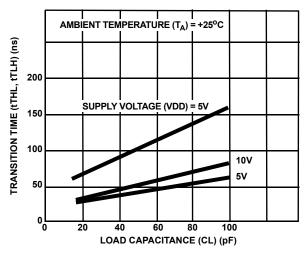


FIGURE 13. TYPICAL TRANSITION TIME AS A FUNCTION OF LOAD CAPACITANCE

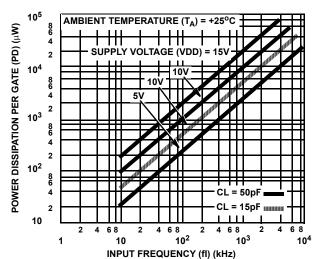
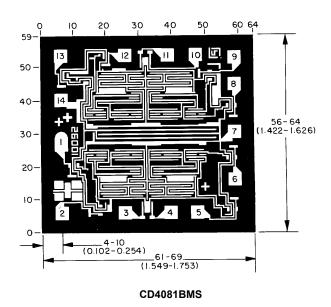
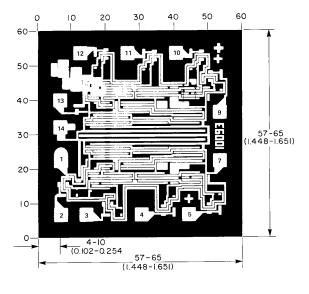


FIGURE 14. TYPICAL DYNAMIC POWER DISSIPATIONPER
GATE AS A FUNCTION OF FREQUENCY

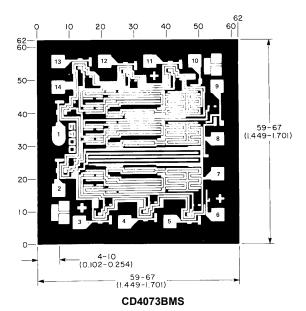
Chip Dimensions and Pad Layouts





CD4082BMS

Chip Dimensions and Pad Layouts



Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated.

Grid graduations are in mils (10⁻³ inch)

METALLIZATION: Thickness: 11kÅ - 14kÅ, AL.

PASSIVATION: 10.4kÅ - 15.6kÅ, Silane

BOND PADS: 0.004 inches X 0.004 inches MIN **DIE THICKNESS:** 0.0198 inches - 0.0218 inches

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